

## Microstructural impact of anodic coatings on the electrochemical chlorine evolution reaction

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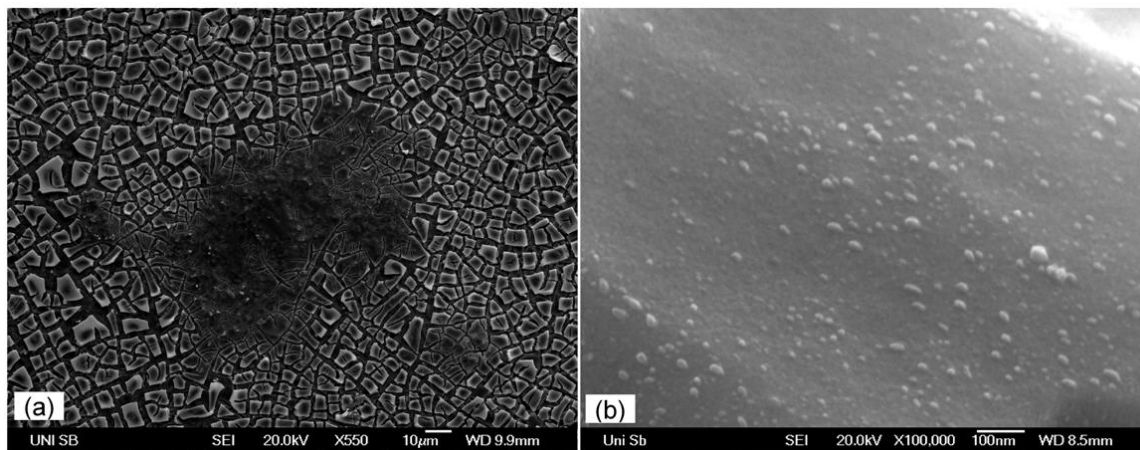
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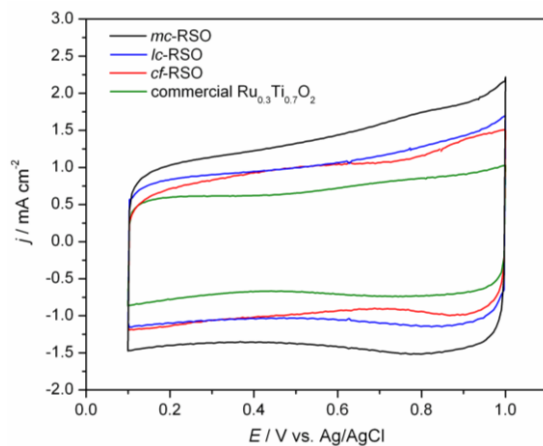
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76021 Karlsruhe, Germany

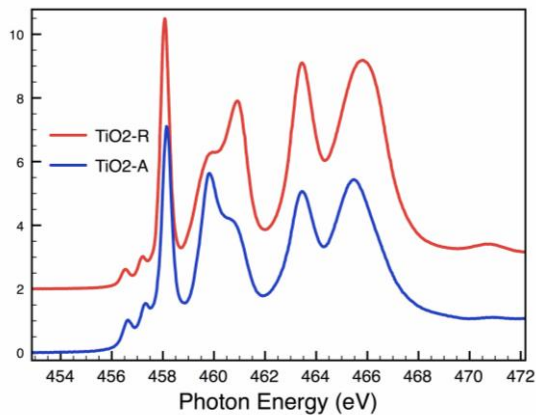
### Supplementary Information



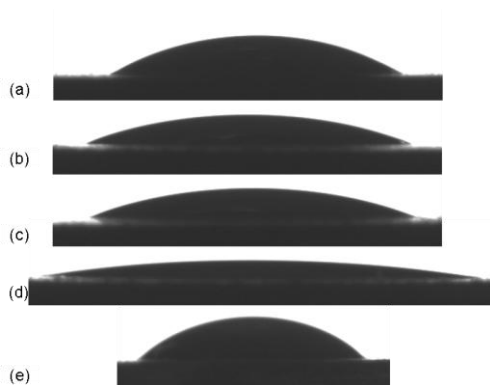
**Fig. S1** SEM images of (a) a commercial  $\text{Ru}_{0.3}\text{Ti}_{0.7}\text{O}_2$  coating, (b) a crack-free sol-gel  $\text{Ru}_{0.25}\text{Ti}_{0.75}\text{O}_2$  coating.<sup>1</sup>



**Fig. S2** Cyclic voltammograms recorded with a potential scan rate of 50 mV s<sup>-1</sup> in 3.5 M NaCl, pH 3, at room temperature.



**Fig. S3** Ti *L*-edge X-ray absorption spectra of the rutile and anatase TiO<sub>2</sub> reference materials.



**Fig. S4** Contact angle measurements in air using a 20 μL water droplet showing the wettability of the coating surface. (a) *mc*-RSO, (b) *rc*-RSO, (c) *lc*-RSO, (d) *cf*-RSO, (e) commercial Ru<sub>0.3</sub>Ti<sub>0.7</sub>O<sub>2</sub> coating. For clarity, the water spreading on the surface is shown without rescaling the images.

**Table S1** XPS surface chemical analysis for the mud-crack  $\text{Ru}_{0.3}\text{Sn}_{0.7}\text{O}_2$  coating as-received and after electrochemical using.

Kinetic energy / eV	Cl/(Ru + Sn)	
	fresh	used
200	0.030	0.165
450	0.041	0.120
700	0.028	0.066

**Reference:**

- 1 R. Chen, V. Trieu, H. Natter, R. Hempelmann, A. Bulan, J. Kintrup and R. Weber, DE102010043085.4, 2010.